PW PACKAGE

SLVS073A - SEPTEMBER 1992 - REVISED AUGUST 1995

- Very Low-Dropout Voltage . . . Less Than 400 mV at 300 mA
- Standby Mode Reduces Current to a Maximum of 150 μA
- Output Regulated to Within ±2% Over Full Temperature Range
- Packaged in Thin Shrink Small-Outline Package
- Only 10-μF Load Capacitor Required to Maintain Regulation at I_O = 300 mA

description

The TL75LPxxQ devices are low-dropout voltage regulators specifically targeted for use in portable applications. These devices generate fixed output voltages at loads of up to 300 mA with only 400-mV dropout over the full temperature range.

Low-dropout voltage regulators are commonly used in battery-powered systems such as analog and digital cellular phones. The TL75LPxx family of regulators feature a TTL/CMOS-compatible enable terminal, which can be used to switch the device into standby mode. This feature reduces power consumption when the instrument is not active. Less that 150 μA is required when the unit is disabled.

A concern in many new designs is conservation of board space and overall reduction in equipment size. The thin shrink small-outline package (TSSOP) minimizes board area and reduces

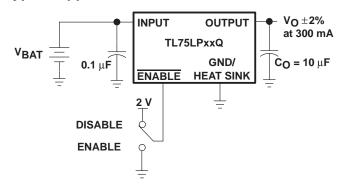
(TOP VIEW) 20 NC GND/HEAT SINK [] 19 NC 2 GND/HEAT SINK [] 3 18 NC 17 NC NC II NC [5 16 NC ENABLE 6 15 OUTPUT NC 7 14 OUTPUT INPUT [] 8 Пис INPUT [] 9 12 NC INPUT [] 11 NC

GND/HEAT SINK – These terminals have an internal connection to ground and must be grounded.

NC – No internal connection

†The PW package is only available in left-end taped and reeled (order device TL75LPxxQPWLE).

typical application schematic



component height. This package has a maximum height of less than 1.1 mm (compared to the 1.75 mm of a standard 8-pin SO package) and dimensions of only 6.5 mm by 4.4 mm.

All low-dropout regulators require an external capacitor at the output to maintain regulation and stability. To further reduce board area and cost, the TL75LPxx devices are designed to require a minimum capacitor of only 10 μ F. This is 1/10 the typical value used by many other low-dropout regulators. To simplify the task of choosing a suitable capacitor, TI has included in this datasheet a list of recommended capacitors for use with these devices.

The TL75LPxxQ devices are characterized for operation over $T_{.1} = -40^{\circ}\text{C}$ to 125°C.

AVAILABLE OPTIONS

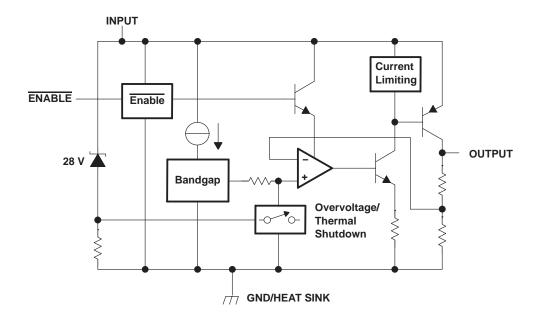
| *************************************** | | | | | | | | |
|---|------------------|------|-------|------------------|-----------|--|--|--|
| | | ٧o | | PACKAGED DEVICES | OUID FORM | | | |
| TJ | | •0 | | TSSOP | CHIP FORM | | | |
| ., | MIN TYP MAX (PW) | | | (Y) | | | | |
| | 4.75 | 4.85 | 4.95 | TL75LP48QPWLE | TL75LP48Y | | | |
| | 4.9 | 5 | 5.1 | TL75LP05QPWLE | TL75LP05Y | | | |
| -40°C to 125°C | 7.84 | 8 | 8.16 | TL75LP08QPWLE | TL75LP08Y | | | |
| | 9.8 | 10 | 10.2 | TL75LP10QPWLE | TL75LP10Y | | | |
| | 11.76 | 12 | 12.24 | TL75LP12QPWLE | TL75LP12Y | | | |

The PW package is available only in tape and reel. Chip forms are tested at 25°C.



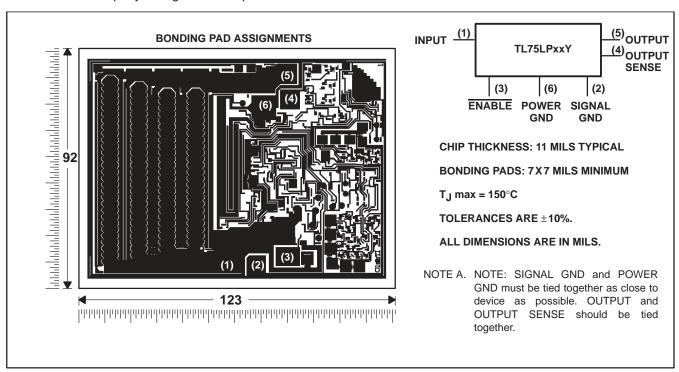
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functional block diagram



TL75LPxxY chip information

This chip, when properly assembled, displays characteristics similar to the TL75LPxx. Thermal compression or ultrasonic bonding can be used on the doped aluminum bonding pads. The chip can be mounted with conductive epoxy or a gold-silicon preform.



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

| Supply voltage, V _{CC} , (See Note 1) | 25 V |
|--|--------------------------------|
| Output current, IO | |
| Operating virtual junction temperature range, T _J | –55°C to 150°C |
| Continuous total power dissipation (see Note 2) | . See Dissipation Rating Table |
| Storage temperature range, T _{stg} | –65°C to 150°C |
| Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds | |

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values are with respect to network terminal ground.

2. Refer to Figures 1 and 2 to avoid exceeding the design maximum virtual junction temperature; these ratings should not be exceeded. Due to variation in individual device electrical characteristics and thermal resistance, the built-in thermal overload protection may be activated at power levels slightly above or below the rated dissipation.

DISSIPATION RATING TABLE

| PACKAGE | POWER RATING AT | $T \leq 25^{\circ}C$ POWER RATING | DERATING FACTOR ABOVE T = 25°C | T = 70°C POWER RATING | T = 85°C POWER RATING | T = 125°C POWER RATING |
|---------|--------------------|-----------------------------------|-----------------------------------|--------------------------|--------------------------|---------------------------|
| | TA | 828 mW | 6.62 mW/°C | 530 mW | 431 mW | 166 mW |
| PW | T_C | 4032 mW | 32.2 mW/°C | 2583 mW | 2100 mW | 812 mW |
| | T _P ‡ | 2475 mW | 19.8 mW/°C | 1584 mW | 1287 mW | 495 mW |

 $^{^{\}ddagger}R_{\theta JP}$ is the thermal resistance between the junction and the device pin. To determine the virtual junction temperature (T_J) relative to the device pin temperature, the following calculations should be used: T_J = P_D x R_{θ JP} + T_P, where P_D is the internal power dissipation of the device and T_P is the device pin temperature at the point of contact to the printed wiring board. The R_{θ JP} for the TL75LPxx series is 50.5°C/W.

MAXIMUM CONTINUOUS DISSIPATION

vs FREE-AIR TEMPERATURE

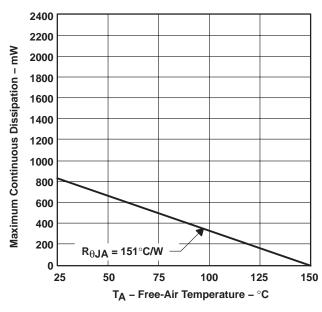


Figure 1

MAXIMUM CONTINUOUS DISSIPATION

vs CASE TEMPERATURE

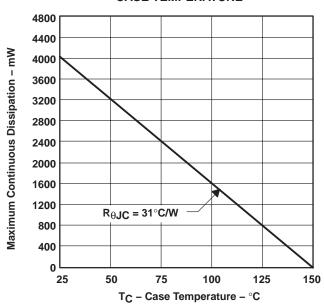


Figure 2

TL75LPxxQ SERIES TL75LPxxY SERIES LOW-DROPOUT VOLTAGE REGULATORS

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recommended operating conditions

| | | MIN | MAX | UNIT |
|--|--------------------|------|------|------|
| | TL75LP48 | 5.15 | 23.0 | |
| | TL75LP05 | 5.3 | 23.0 | |
| Input voltage, V _I | TL75LP08 | 8.4 | 23.0 | V |
| | TL75LP10 | 10.4 | 23.0 | |
| | TL75LP12 12.5 23.0 | | | |
| High-level input voltage, ENABLE, VIH | | 2.0 | 15.0 | V |
| Low-level input voltage, ENABLE, V _{IL} | | 0 | 0.8 | V |
| Output current range, IO | | 5 | 300 | mA |
| Operating virtual junction temperature range, TJ | | -40 | 125 | °C |

electrical characteristics over operating virtual junction temperature range, $V_I = 10 \text{ V}$, $I_O = 300 \text{ mA}$, ENABLE = 0 V (unless otherwise noted)

| 24244555 | TEGT CONDITIONS! | TL | | | |
|----------------------------------|--|--|------|------|------|
| PARAMETER | TEST CONDITIONS† | MIN | TYP | MAX | UNIT |
| Output voltage | V _I = 5.35 V to 10 V | 4.75 | 4.85 | 4.95 | V |
| Input voltage regulation | V _I = 5.35 V to 10 V, T _J = 25°C | | 10 | 25 | mV |
| Ripple rejection | $V_{I} = 5.6 \text{ V to } 15.6 \text{ V}, f = 120 \text{ Hz}, T_{J} = 25^{\circ}\text{C}$ | 50 | 55 | | dB |
| Output voltage regulation | $I_{O} = 5 \text{ mA to } 300 \text{ mA}, T_{J} = 25^{\circ}\text{C}$ | | 12 | 30 | mV |
| Dropout voltage | I _O = 100 mA | | 0.12 | 0.2 | |
| | I _O = 200 mA | | 0.17 | 0.3 | V |
| | I _O = 300 mA | | 0.22 | 0.4 | |
| Output noise voltage | f = 10 Hz to 100 kHz, T _J = 25°C | | 500 | | μV |
| | I _O = 10 mA | | 2.5 | 4 | |
| 5: | $I_{O} = 100 \text{ mA}$ | 4.75 4.85 4.95 10 25 50 55 12 30 0.12 0.2 0.17 0.3 0.22 0.4 500 | 10 | | |
| Bias current | $I_{O} = 200 \text{ mA}$ | | 6 | 20 | mA |
| | $I_{O} = 300 \text{ mA}$ | | 9 | 30 | |
| High-level input current, ENABLE | ENABLE = 0.8 V | | 7 | 25 | μΑ |
| Low-level input current, ENABLE | ENABLE = 2 V | | 0.05 | 6 | μΑ |
| Standby current | ENABLE = 2 V | | 100 | 150 | μΑ |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.

<u>electrical</u> characteristics over operating virtual junction temperature range, $V_I = 10 \text{ V}$, $I_O = 300 \text{ mA}$, ENABLE = 0 V (unless otherwise noted)

| 2424455 | TEGT COMPLETIONS | TL75LP05Q | | | | |
|----------------------------------|---|-----------|------|-----|------|--|
| PARAMETER | TEST CONDITIONS [†] | MIN | TYP | MAX | UNIT | |
| Output voltage | $V_{I} = 5.5 \text{ V to } 10 \text{ V}$ | 4.9 | 5 | 5.1 | V | |
| Input voltage regulation | $V_{I} = 5.5 \text{ V to } 10 \text{ V}, \qquad T_{J} = 25^{\circ}\text{C}$ | | 10 | 25 | mV | |
| Ripple rejection | $V_{I} = 6 \text{ V to } 16 \text{ V}, \qquad \qquad f = 120 \text{ Hz}, T_{J} = 25^{\circ}\text{C}$ | 50 | 55 | | dB | |
| Output voltage regulation | $I_{O} = 5 \text{ mA to } 300 \text{ mA}, T_{J} = 25^{\circ}\text{C}$ | | 12 | 30 | mV | |
| Dropout voltage | I _O = 100 mA | | 0.12 | 0.2 | | |
| | I _O = 200 mA | | 0.17 | 0.3 | V | |
| | I _O = 300 mA | | 0.22 | 0.4 | | |
| Output noise voltage | f = 10 Hz to 100 kHz, T _J = 25°C | | 500 | | μV | |
| | I _O = 10 mA | | 2.5 | 4 | | |
| B'as summed | I _O = 100 mA | | 4 | 10 | 4 | |
| Bias current | $I_{O} = 200 \text{ mA}$ | | 6 | 20 | mA | |
| | $I_{O} = 300 \text{ mA}$ | | 9 | 30 | | |
| High-level input current, ENABLE | ENABLE = 0.8 V | | 7 | 25 | μΑ | |
| Low-level input current, ENABLE | ENABLE = 2 V | | 0.05 | 6 | μΑ | |
| Standby current | ENABLE = 2 V | | 100 | 150 | μΑ | |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.

<u>electrical</u> characteristics over operating virtual junction temperature range, $V_I = 10 \text{ V}$, $I_O = 300 \text{ mA}$, ENABLE = 0 V (unless otherwise noted)

| | | TL | | | |
|--|--|------|------|------|------|
| PARAMETER | TEST CONDITIONS† | MIN | TYP | MAX | UNIT |
| Output voltage | V _I = 8.6 V to 15 V | 7.84 | 8 | 8.16 | V |
| Input voltage regulation | $V_{I} = 8.6 \text{ V to } 15 \text{ V}, \qquad T_{J} = 25^{\circ}\text{C}$ | | 12 | 40 | mV |
| Ripple rejection | $V_{I} = 9 \text{ V to } 19 \text{ V}, \qquad f = 120 \text{ Hz}, T_{J} = 25^{\circ}\text{C}$ | 50 | 55 | | dB |
| Output voltage regulation | $I_{O} = 5 \text{ mA to } 300 \text{ mA}, T_{J} = 25^{\circ}\text{C}$ | | 12 | 40 | mV |
| Dropout voltage | I _O = 100 mA | | 0.12 | 0.2 | |
| | $I_{O} = 200 \text{ mA}$ | | 0.17 | 0.3 | V |
| | I _O = 300 mA | | 0.22 | 0.4 | |
| Output noise voltage | $f = 10 \text{ Hz to } 100 \text{ kHz}, T_J = 25^{\circ}\text{C}$ | | 500 | | μV |
| | I _O = 10 mA | | 2.5 | 4 | |
| Output voltage regulation $I_{O} = 5 \text{ mA to } 300 \text{ mA}, T_{J} = 25^{\circ}\text{C}$ $I_{O} = 100 \text{ mA}$ $I_{O} = 200 \text{ mA}$ $I_{O} = 300 \text{ mA}$ $I_{O} = 300 \text{ mA}$ Output noise voltage $f = 10 \text{ Hz to } 100 \text{ kHz}, T_{J} = 25^{\circ}\text{C}$ | | 4 | 10 | | |
| Bias current | I _O = 200 mA | | 6 | 20 | mA |
| | I _O = 300 mA | | 9 | 30 | 1 |
| High-level input current, ENABLE | ENABLE = 0.8 V | | 7 | 25 | μΑ |
| Low-level input current, ENABLE | ENABLE = 2 V | | 0.05 | 6 | μΑ |
| Standby current | ENABLE = 2 V | | 100 | 150 | μΑ |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.



<u>electrical</u> characteristics over operating virtual junction temperature range, $V_I = 14 \text{ V}$, $I_O = 300 \text{ mA}$, <u>ENABLE</u> = 0 V (unless otherwise noted)

| | TEGT COMPLTIONS | TL75LP10Q | | | | |
|----------------------------------|---|-----------|------|------|------|--|
| PARAMETER | TEST CONDITIONS† | MIN | TYP | MAX | UNIT | |
| Output voltage | V _I = 10.6 V to 17 V | 9.8 | 10 | 10.2 | V | |
| Input voltage regulation | $V_{I} = 10.6 \text{ V to } 17 \text{ V}, \qquad T_{J} = 25^{\circ}\text{C}$ | | 15 | 43 | mV | |
| Ripple rejection | $V_{I} = 11 \text{ V to } 21 \text{ V}, \qquad f = 120 \text{ Hz}, T_{J} = 25^{\circ}\text{C}$ | 50 | 55 | | dB | |
| Output voltage regulation | $I_{O} = 5 \text{ mA to } 300 \text{ mA}, T_{J} = 25^{\circ}\text{C}$ | | 15 | 50 | mV | |
| | I _O = 100 mA | | 0.12 | 0.2 | | |
| Dropout voltage | I _O = 200 mA | | 0.17 | 0.3 | V | |
| | I _O = 300 mA | | 0.22 | 0.4 | | |
| Output noise voltage | f = 10 Hz to 100 kHz, T _J = 25°C | | 1000 | | μV | |
| | I _O = 10 mA | | 2.5 | 4 | | |
| B'as summed | I _O = 100 mA | | 4 | 10 | 4 | |
| Bias current | $I_{O} = 200 \text{ mA}$ | | 6 | 20 | mA | |
| | $I_{O} = 300 \text{ mA}$ | | 9 | 30 | | |
| High-level input current, ENABLE | ENABLE = 0.8 V | | 7 | 25 | μΑ | |
| Low-level input current, ENABLE | ENABLE = 2 V | | 0.05 | 6 | μΑ | |
| Standby current | ENABLE = 2 V | | 100 | 150 | μΑ | |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.

<u>electrical</u> characteristics over operating virtual junction temperature range, $V_I = 14 \text{ V}$, $I_O = 300 \text{ mA}$, ENABLE = 0 V (unless otherwise noted)

| | | TL | | | |
|----------------------------------|---|--|------|-------|----|
| PARAMETER | TEST CONDITIONS! | TL75LP120 MIN TYP 11.76 12 50 55 15 0.12 0.12 0.17 0.22 1000 2.5 4 6 6 | MAX | UNIT | |
| Output voltage | V _I = 12.7 V to 18 V | 11.76 | 12 | 12.24 | V |
| Input voltage regulation | V _I = 12.7 V to 18 V, T _J = 25°C | | 15 | 43 | mV |
| Ripple rejection | $V_{I} = 13 \text{ V to } 23 \text{ V}, \qquad f = 120 \text{ Hz}, T_{J} = 25^{\circ}\text{C}$ | 50 | 55 | | dB |
| Output voltage regulation | I _O = 5 mA to 300 mA, T _J = 25°C | | 15 | 60 | mV |
| Dropout voltage | I _O = 100 mA | | 0.12 | 0.2 | |
| | I _O = 200 mA | | 0.17 | 0.3 | V |
| | IO = 300 mA | | 0.22 | 0.4 | |
| Output noise voltage | f = 10 Hz to 100 kHz, T _J = 25°C | | 1000 | | μV |
| | I _O = 10 mA | | 2.5 | 4 | |
| 5 . | V _I = 12.7 V to 18 V 11.76 12 12 V _I = 12.7 V to 18 V, T _J = 25°C 15 V _I = 13 V to 23 V, f = 120 Hz, T _J = 25°C 50 55 I _O = 5 mA to 300 mA, T _J = 25°C 15 I _O = 100 mA 0.12 0.12 I _O = 200 mA 0.17 0.22 f = 10 Hz to 100 kHz, T _J = 25°C 1000 I _O = 10 mA 2.5 1000 I _O = 100 mA 4 4 I _O = 200 mA 6 6 I _O = 300 mA 9 7 ENABLE = 2 V 0.05 | 10 | | | |
| Bias current | I _O = 200 mA | | 6 | 20 | mA |
| | IO = 300 mA | | 9 | 30 | 1 |
| High-level input current, ENABLE | ENABLE = 0.8 V | | 7 | 25 | μΑ |
| Low-level input current, ENABLE | ENABLE = 2 V | | 0.05 | 6 | μΑ |
| Standby current | ENABLE = 2 V | | 100 | 150 | μΑ |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.



electrical characteristics at $V_I = 10 \text{ V}$, $I_O = 300 \text{ mA}$, $\overline{\text{ENABLE}} = 0 \text{ V}$, $T_J = 25^{\circ}\text{C}$ (unless otherwise noted)

| 242445 | TEST SOMETIONS! | TL | | | |
|----------------------------------|----------------------|-----|------|-----|------|
| PARAMETER | TEST CONDITIONS† | MIN | TYP | MAX | UNIT |
| Output voltage | | | 4.85 | | V |
| Input voltage regulation | | | 10 | | mV |
| Ripple rejection | f = 120 Hz | | 55 | | dB |
| Output voltage regulation | | | 12 | | mV |
| Dropout voltage | | | 0.22 | | V |
| Output noise voltage | f = 10 Hz to 100 kHz | | 500 | | μV |
| Bias current | | | 9 | | mA |
| High-level input current, ENABLE | ENABLE = 0.8 V | | 7 | | μΑ |
| Low-level input current, ENABLE | ENABLE = 2 V | | 0.05 | | μΑ |
| Standby current | ENABLE = 2 V | | 100 | | μΑ |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.

electrical characteristics at $V_I = 10 \text{ V}$, $I_O = 300 \text{ mA}$, $\overline{\text{ENABLE}} = 0 \text{ V}$, $T_J = 25^{\circ}\text{C}$ (unless otherwise noted)

| | | TL75LP05Y | l |
|----------------------------------|----------------------|-------------|------|
| PARAMETER | TEST CONDITIONS† | MIN TYP MAX | UNIT |
| Output voltage | | 5 | V |
| Input voltage regulation | | 10 | mV |
| Ripple rejection | f = 120 Hz | 55 | dB |
| Output voltage regulation | | 12 | mV |
| Dropout voltage | | 0.22 | V |
| Output noise voltage | f = 10 Hz to 100 kHz | 500 | μV |
| Bias current | | 9 | mA |
| High-level input current, ENABLE | ENABLE = 0.8 V | 7 | μΑ |
| Low-level input current, ENABLE | ENABLE = 2 V | 0.05 | μΑ |
| Standby current | ENABLE = 2 V | 100 | μΑ |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.

TL75LPxxQ SERIES TL75LPxxY SERIES LOW-DROPOUT VOLTAGE REGULATORS

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electrical characteristics at V_I = 10 V, I_O = 300 mA, ENABLE = 0 V, T_{.J} = 25°C (unless otherwise noted)

| DADAMETER | TEST SOURITIONS! | TL | | | |
|----------------------------------|----------------------|-----|------|-----|------|
| PARAMETER | TEST CONDITIONS† | MIN | TYP | MAX | UNIT |
| Output voltage | | | 8 | | V |
| Input voltage regulation | | | 12 | | mV |
| Ripple rejection | f = 120 Hz | | 55 | | dB |
| Output voltage regulation | | | 12 | | mV |
| Dropout voltage | | | 0.22 | | V |
| Output noise voltage | f = 10 Hz to 100 kHz | | 500 | | μV |
| Bias current | | | 9 | | mA |
| High-level input current, ENABLE | ENABLE = 0.8 V | | 7 | | μΑ |
| Low-level input current, ENABLE | ENABLE = 2 V | | 0.05 | | μΑ |
| Standby current | ENABLE = 2 V | | 100 | | μΑ |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.

electrical characteristics at V_I = 14 V, I_O = 300 mA, ENABLE = 0 V, T_{.J} = 25°C (unless otherwise noted)

| DADAMETED | TEST CONDITIONS | TL75LP10Y | UNIT |
|----------------------------------|----------------------|-------------|------|
| PARAMETER | TEST CONDITIONS† | MIN TYP MAX | |
| Output voltage | | 10 | V |
| Input voltage regulation | | 15 | mV |
| Ripple rejection | f = 120 Hz | 55 | dB |
| Output voltage regulation | | 15 | mV |
| Dropout voltage | | 0.22 | V |
| Output noise voltage | f = 10 Hz to 100 kHz | 1000 | μV |
| Bias current | | 9 | mA |
| High-level input current, ENABLE | ENABLE = 0.8 V | 7 | μΑ |
| Low-level input current, ENABLE | ENABLE = 2 V | 0.05 | μΑ |
| Standby current | ENABLE = 2 V | 100 | μΑ |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.

TL75LPxxQ SERIES TL75LPxxY SERIES LOW-DROPOUT VOLTAGE REGULATORS SLVS073A - SEPTEMBER 1992 - REVISED AUGUST 1995

electrical characteristics at $V_I = 14 \text{ V}$, $I_O = 300 \text{ mA}$, $\overline{\text{ENABLE}} = 0 \text{ V}$, $T_J = 25^{\circ}\text{C}$ (unless otherwise noted)

| DADAMETER | TEST CONDITIONS† | TL75LP12Y | | | |
|----------------------------------|----------------------|-----------|------|-------|------|
| PARAMETER | | MIN | TYP | MAX | UNIT |
| Output voltage | | 11.76 | 12 | 12.24 | V |
| Input voltage regulation | | | 15 | 43 | mV |
| Ripple rejection | f = 120 Hz | | 55 | | dB |
| Output voltage regulation | | | 12 | 60 | mV |
| Dropout voltage | | | 0.22 | 0.4 | V |
| Output noise voltage | f = 10 Hz to 100 kHz | | 500 | | μV |
| Bias current | | | 9 | 30 | mA |
| High-level input current, ENABLE | ENABLE = 0.8 V | | 7 | 25 | μА |
| Low-level input current, ENABLE | ENABLE = 2 V | | 0.05 | 6 | μΑ |
| Standby current | ENABLE = 2 V | | 100 | 150 | μΑ |

[†] Pulse-testing techniques maintain the virtual junction temperature as close to the ambient temperature as possible. Thermal effects must be taken into account separately. All characteristics are measured with a 0.1-μF capacitor across the input and a 10-μF capacitor with equivalent series resistance within the guidelines shown in Figures 3 and 4 on the output. All measurements are taken with a tantalum electrolytic capacitor. Although not normally recommended, an aluminum electrolytic capacitor can be used. Attention must be given its ESR value, particularly at low temperatures.

PARAMETER MEASUREMENT INFORMATION

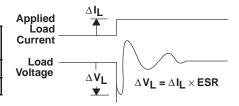
The TL75LPxx series are low-dropout voltage regulators. This means that the capacitance is important to the performance of the regulator because it is a vital part of the control loop. The capacitor value and the equivalent series resistance (ESR) both affect the control loop and must be defined for the load range and the temperature range. Figures 3 and 4 can establish the capacitance value and ESR range for optimum regulator performance.

Figure 3 shows the recommended range of ESR, measured at 120 Hz, for a given load with a 10- μ F capacitor on the output. In addition, it shows a maximum ESR limit of 2 Ω and a load-dependent minimum ESR limit.

For applications with varying loads, the lightest load condition should be chosen since it is the worst case. Figure 4 shows the relationship of the reciprocal of ESR to the square root of the capacitance with a minimum capacitance limit of 10 μ F and a maximum ESR limit of 2 Ω . Figure 4 establishes the amount that the minimum ESR limit of Figure 3 can be adjusted for different capacitor values. For example, when the minimum load needed is 200 mA, Figure 3 suggests an ESR range of 0.8 Ω to 2 Ω for 10 μ F. Figure 4 shows that changing the capacitor from 10 μ F to 400 μ F can change the ESR minimum by greater than 3/0.5 (or 6). Therefore, the new minimum ESR value is 0.8/6 (or 0.13 Ω). This now allows an ESR range of 0.13 Ω to 2 Ω . This expanded ESR range is achieved by using a larger capacitor at the output. For better stability in low-current applications, it is recommended that a small resistance be placed in series with the capacitor (see Table 1) so that the ESR better approximates those in Figures 3 and 4.

Table 1. Compensations for Increased Stability at Low Currents

| | MANUFACTURER | CAPACITANCE | ESR TYP | PART NUMBER | ADDITIONAL RESISTANCE |
|---|--------------|-------------|------------|----------------|-----------------------|
| ı | AVX | 15 μF | 0.9 Ω | TAJB156M010S | 1 Ω |
| ı | KEMET | 33 μF | 0.6 Ω | T491D336M010AS | 0.5Ω |



OUTPUT CAPACITOR EQUIVALENT SERIES RESISTANCE vs LOAD CURRENT

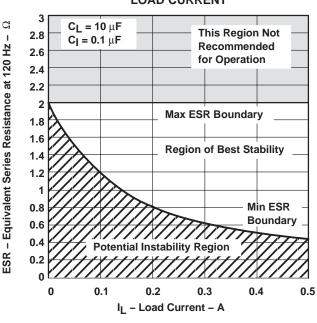
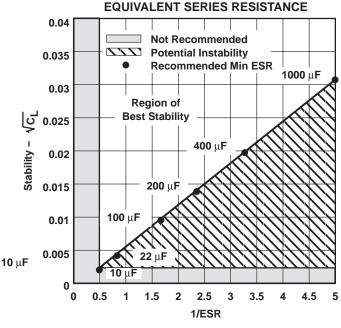


Figure 3

OUTPUT CAPACITOR STABILITY vs



TYPICAL CHARACTERISTICS

Table of Graphs

| | | | FIGURE |
|--|-------------------------|-------------------|--------|
| Output voltage | | vs Input voltage | 5 |
| | I _O = 10 mA | vs Input voltage | 6 |
| Input current | I _O = 100 mA | vs Input voltage | 7 |
| Dropout voltage | | vs Output current | 8 |
| Quiescent current | | vs Output current | 9 |
| Short-circuit protection conditions output voltage | | vs Output current | 10 |
| Load transient response | | | 11 |
| Line transient response | | | 12 |

TYPICAL CHARACTERISTICS

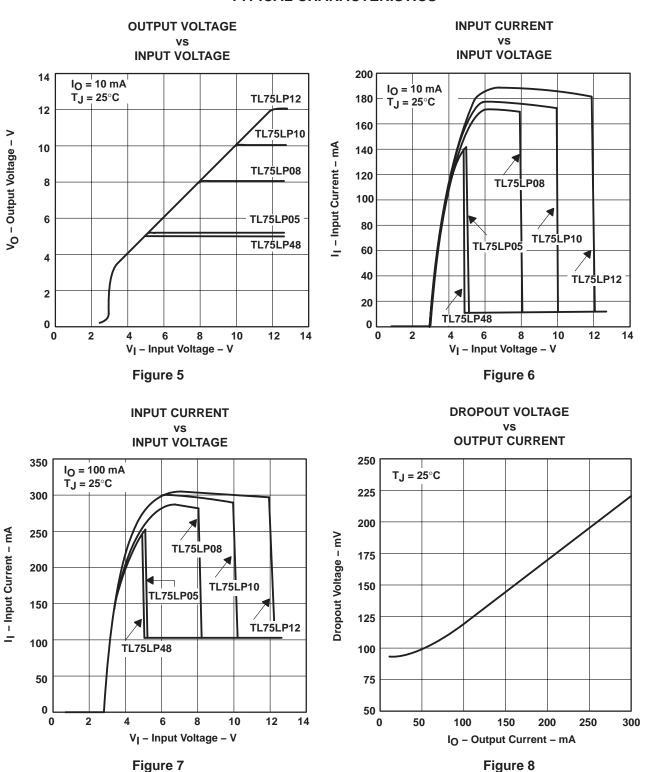




Figure 8

TYPICAL CHARACTERISTICS

QUIESCENT CURRENT vs **OUTPUT CURRENT** 12 T_J = 25°C V_I = 14 V 10 IQ - Quiescent Current - mA 8 6 2 0 20 40 60 80 100 120 140 160 IO - Output Current - mA

Figure 9

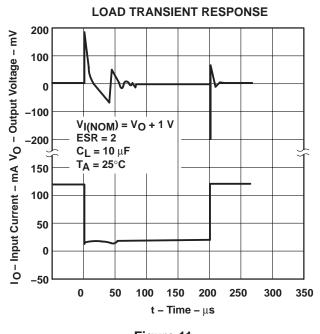


Figure 11

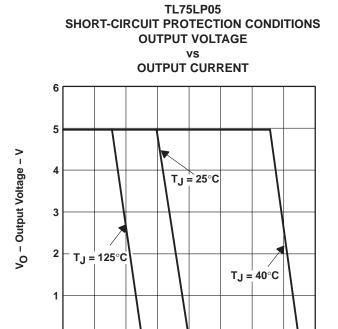


Figure 10

1.05 1.15 1.25 1.35

IO - Output Current - A

1.45 1.55

0.75

0.85 0.95

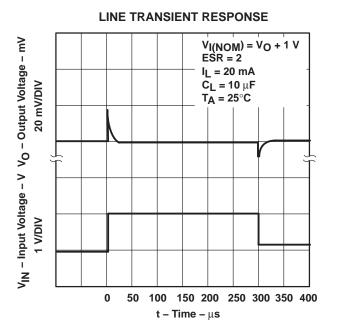


Figure 12

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